

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10518090	NAGASHIMA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	HANG PAN	2193

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
717	137	10/14/2009	HP

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST search, see attachment	10/14/2009	HP
PLUS search, see eDAN	10/14/2009	HP
Inventor's name search in EAST	10/14/2009	HP
Text search in class 717	10/14/2009	HP
NPL search in Google scholar, see attachment	10/14/2009	HP
Updated EAST search, see attachment	6/16/2010	HP
NPL search in Google Scholar, see attachment	6/16/2010	HP
EIC search	6/16/2010	HP
Consulted with Jason Mitchell, class 717	6/16/2010	HP

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
717	110, 122, 136, 137	6/16/2010	HP

/H. P./  
Examiner.Art Unit 2193